QUALIFICATION REPORT SUMMARY

PCN #: CENO-15OQGJ217

Date:
March 05, 2026

Qualification of ASSH and MTAI as an additional final test sites for AT25080B-XHL-B, AT25080B-XHL-T, AT25160B-XHL-B, AT25160B-XHL-T catalog part numbers (CPN) and qualification of ASSH as an additional final test site for selected 25LC080D, 25LC160C, 25LC160D, 25AA080C, 25AA080D, 25AA160C, 25AA160D, and 25LC080C devices families in 8L TSSOP (4.4mm) package, together with qualification of MTAI as an additional final test site for AT25080B-SSHL-T, AT25080B-SSHL-B, AT25160B-SSHL-B, and AT25160B-SSHL-T catalog part numbers (CPN) available in 8L SOIC (3.90mm) package.

Purpose: Qualification of ASSH and MTAI as an additional final test sites for AT25080B-XHL-B, AT25080B-XHL-T, AT25160B-XHL-B, AT25160B-XHL-T catalog part numbers (CPN) and qualification of ASSH as an additional final test site for selected 25LC080D, 25LC160C, 25LC160D, 25AA080C, 25AA080D, 25AA160C, 25AA160D, and 25LC080C devices families in 8L TSSOP (4.4mm) package, together with qualification of MTAI as an additional final test site for AT25080B-SSHL-T, AT25080B-SSHL-B, AT25160B-SSHL-B, and AT25160B-SSHL-T catalog part numbers (CPN) available in 8L SOIC (3.90mm) package.

CCB No.: 6183.007

Test Name	Test Condition	Result
Test Correlation	Correlation on production ATE in strip form at each site and compare results between the two sites > Build and test (> 3000 pcs.) for checkout in ASSH > Compare test yields from checkout in ASSH with MTAI historic yields > Compare test yields from checkout in MTAI with ANAP historic yields	**Passed**